

N-Channel Enhancement Mode MOSFET

Feature Description

- 200V/90A
- $R_{DS(ON)} = 22m\Omega$ (typ.)@ $V_{GS} = 10V$
- 100% Avalanche Tested
- Reliable and Rugged
- Lead Free and Green Devices Available
(RoHS Compliant)



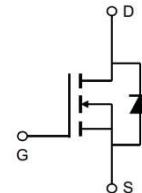
HM90N20
TO-220-3L



HM90N20D
TO-263-2L

Applications

- Power Management for Inverter Systems



N-Channel MOSFET

Ordering and Marking Information

HM90N20 YYWW	HM90N20D YYWW	Package Code HM90N20: TO-220-3L HM90N20D: TO-263-2L
		Date Code YYWW

Note: H&M SEMI lead -free products contain molding compounds/die attach materials and 100% matte tin plate Termi- Nation finish;which are fully compliant with RoHS. H&M SEMI lead -free products meet or exceed the lead-Free require- ments of IPC/JEDEC J-STD-020 for MSL classification at lead-free peak reflow temperature. H&M SEMI defi nes “Green” to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

H&M SEMI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.

Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit	
Common Ratings (T_c=25°C Unless Otherwise Noted)				
V _{DSS}	Drain-Source Voltage	200	V	
V _{GSS}	Gate-Source Voltage	±20	V	
T _J	Maximum Junction Temperature	175	°C	
T _{STG}	Storage Temperature Range	-55 to 175	°C	
I _s	Source Current-Continuous(Body Diode)	90	A	
Mounted on Large Heat Sink				
I _{DM}	Pulsed Drain Current *	T _c =25°C	360	A
I _D	Continuous Drain Current	T _c =25°C	90	A
		T _c =100°C	70	A
P _D	Maximum Power Dissipation	T _c =25°C	375	W
		T _c =100°C	187.5	W
R _{θJC}	Thermal Resistance, Junction-to-Case	0.4	°C/W	
R _{θJA}	Thermal Resistance, Junction-to-Ambient **	62.5	°C/W	
E _{AS}	Single Pulsed-Avalanche Energy ***	L=0.5mH	784	mJ

Note: * Repetitive rating; pulse width limited by max. junction temperature.

** Surface mounted on FR-4 board.

*** Limited by T_{jmax}, starting T_j=25°C, L = 0.5mH, R_G= 25Ω, V_{GS} =10V.

Electrical Characteristics(T_c =25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	<A - \$B&\$			Unit
			Min	Typ.	Max	
Static Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250μA	200	-	-	V
I _{DSS}	Drain-to-Source Leakage Current	V _{DS} =200V, V _{GS} =0V	-	-	1	μA
		T _J =55°C	-	-	5	μA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	2.0	3.0	4.0	V
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
R _{DS(ON)*}	Drain-Source On-State Resistance	V _{GS} =10V, I _{DS} =45A		22.0	24.0	mΩ
Diode Characteristics						
V _{SD*}	Diode Forward Voltage	I _{SD} =45A, V _{GS} =0V	-	0.82	1.1	V
t _{rr}	Reverse Recovery Time	I _{SD} =45A, dI _{SD} /dt=100A/μs	-	80	-	ns
Q _{rr}	Reverse Recovery Charge		-	160	-	nC

Electrical Characteristics (Cont.) ($T_c = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	< A - \$B&\$			Unit
			Min	Typ.	Max	
Dynamic Characteristics						
R_G	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1\text{MHz}$	-	3.4	-	Ω
C_{iss}	Input Capacitance	$V_{GS}=0V,$ $V_{DS}=25V,$ Frequency=1.0MHz	-	5871	-	pF
C_{oss}	Output Capacitance		-	392	-	
C_{rss}	Reverse Transfer Capacitance		-	165	-	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=100V, R_G=4\Omega,$ $I_{DS}=45A, V_{GS}=10V$	-	29	-	ns
T_r	Turn-on Rise Time		-	45	-	
$t_{d(OFF)}$	Turn-off Delay Time		-	22	-	
T_f	Turn-off Fall Time		-	41	-	
Gate Charge Characteristics						
Q_g	Total Gate Charge	$V_{DS}=160V, V_{GS}=10V,$ $I_D=45A$	-	130.4	-	nC
Q_{gs}	Gate-Source Charge		-	22.1	-	
Q_{gd}	Gate-Drain Charge		-	38.2	-	

Note: *Pulse test, pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$

Typical Operating Characteristics

Figure 1: Power Dissipation

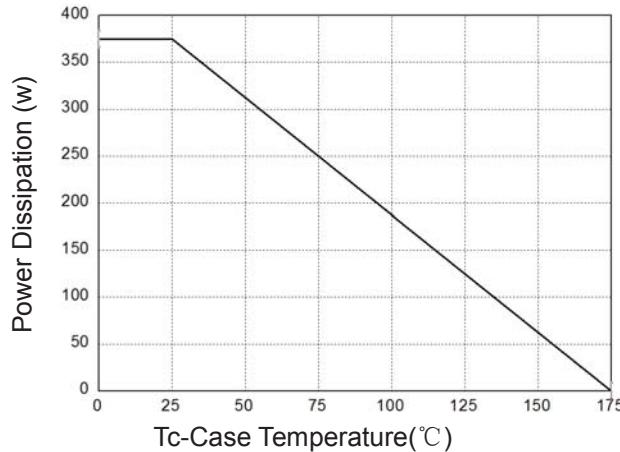


Figure 2: Drain Current

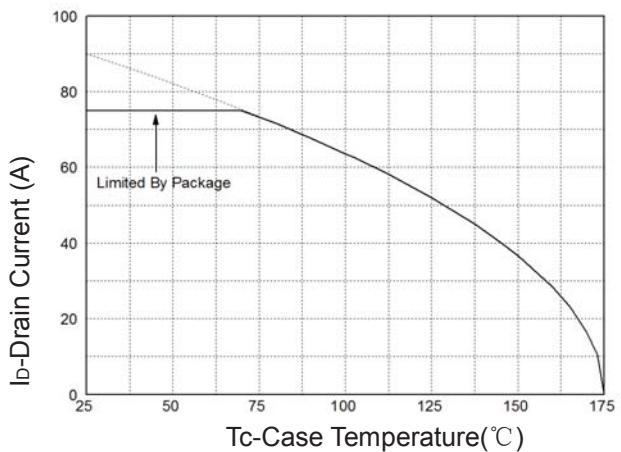


Figure 3: Safe Operation Area

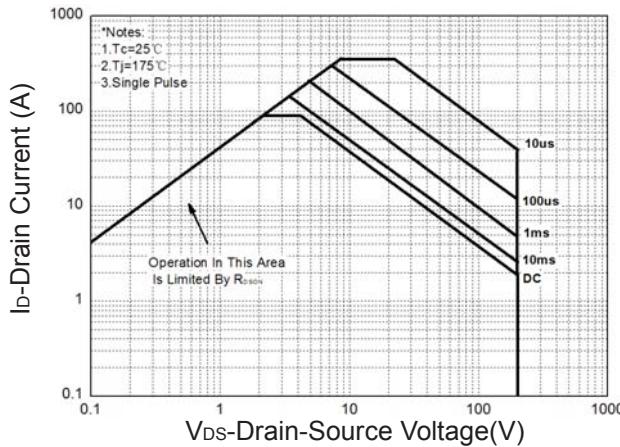


Figure 4: Thermal Transient Impedance

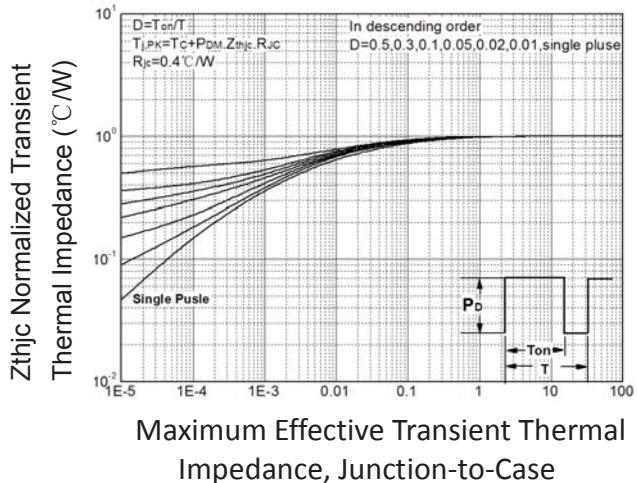


Figure 5: Output Characteristics

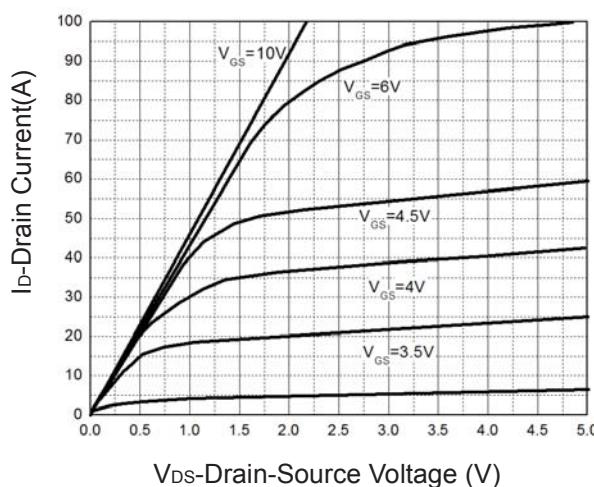
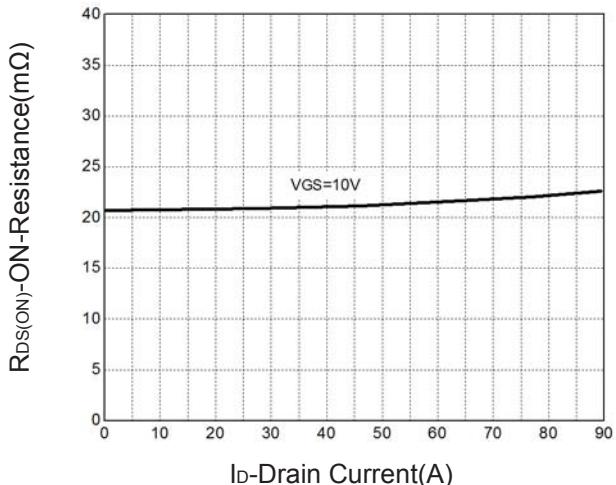


Figure 6: Drain-Source On Resistance



Typical Operating Characteristics(Cont.)

Figure 7: Gate-Source Vs. On-Resistance

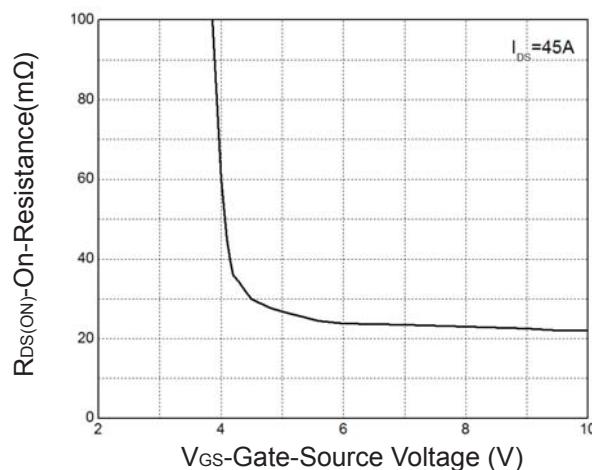


Figure 8: Gate-Source Forward

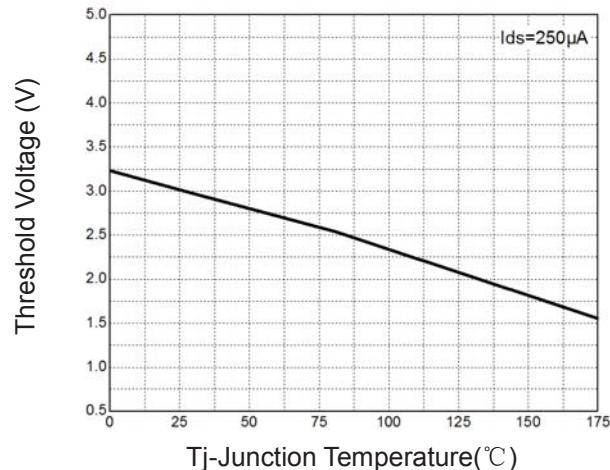


Figure 9: On-Resistance vs. Temperature

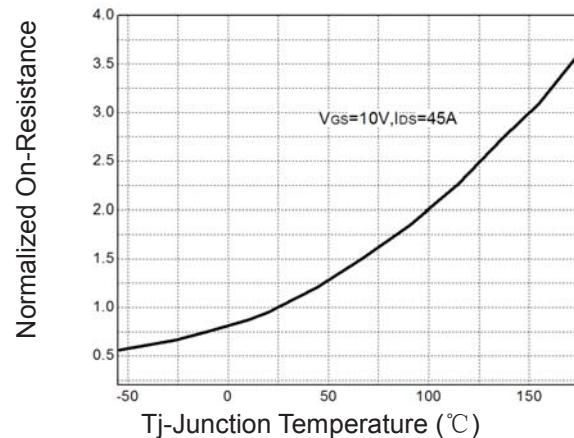


Figure 10: Source-Drain Diode Forward

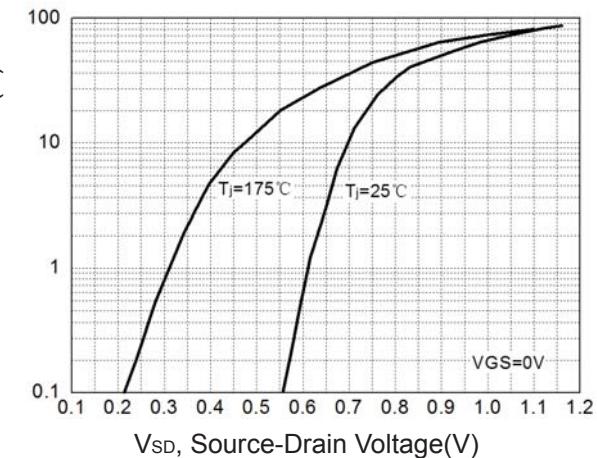


Figure 11: Capacitance Characteristics

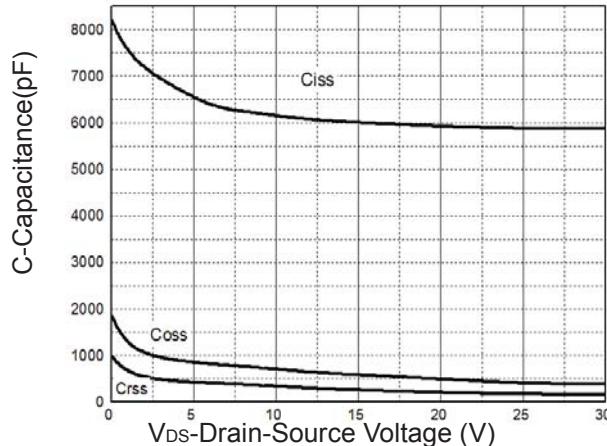
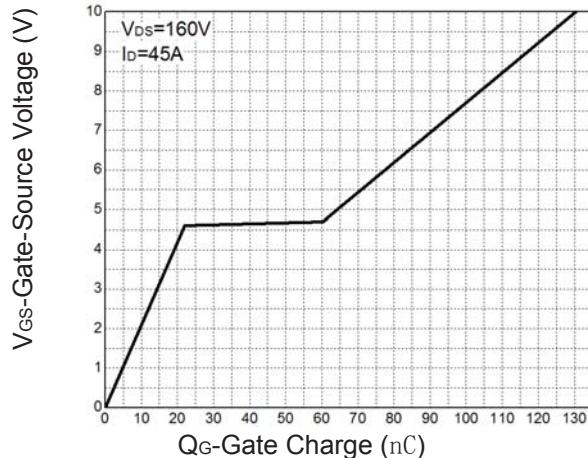
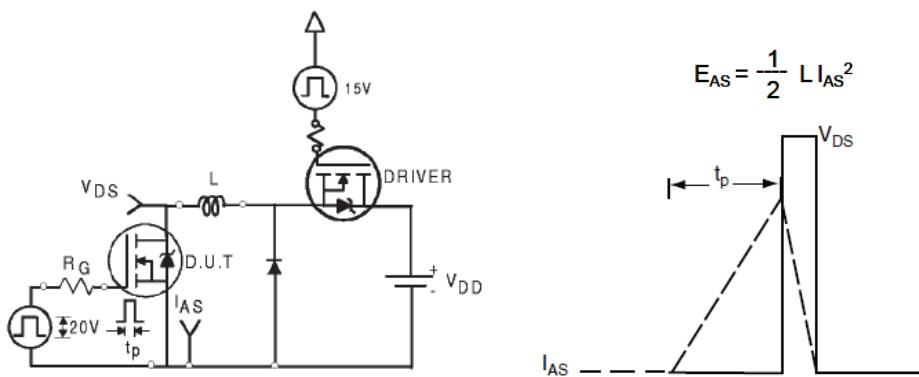


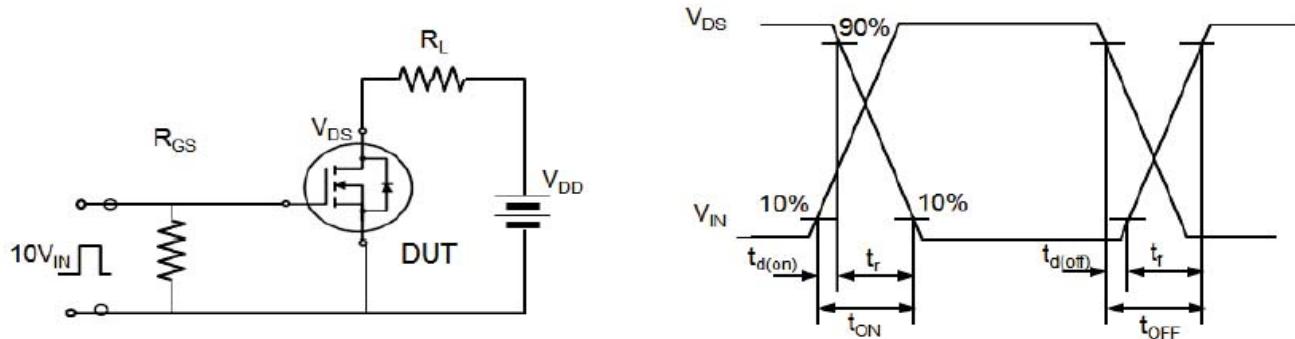
Figure 12: Gate Charge Characteristics



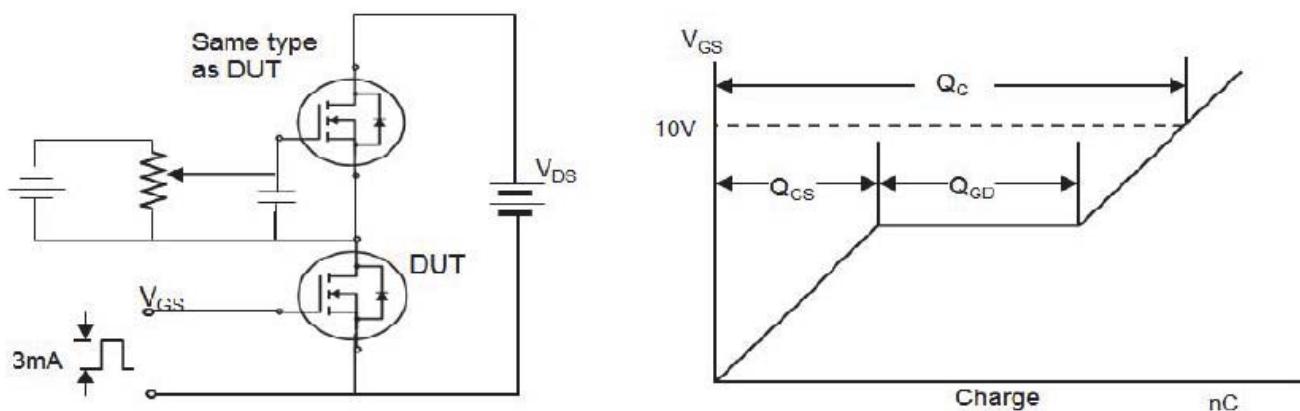
Avalanche Test Circuit



Switching Time Test Circuit



Gate Charge Test Circuit

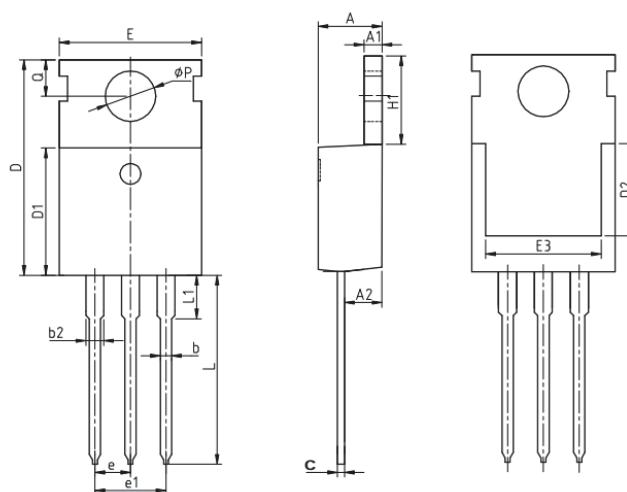


Device Per Unit

Package Type	Unit	Quantity
TO-220-3L	Tube	50

Package Information

TO-220-3L



COMMON DIMENSIONS

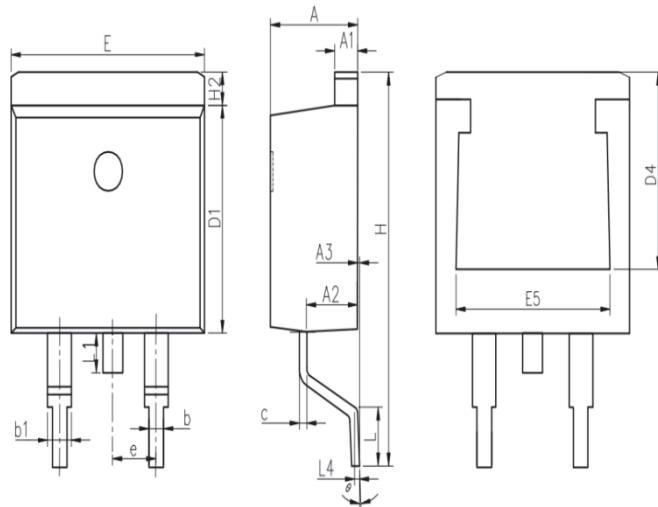
SYMBOL	mm		
	MIN	NOM	MAX
A	4.37	4.57	4.77
A1	1.25	1.30	1.45
A2	2.20	2.40	2.60
b	0.70	0.80	0.95
b2	1.17	1.27	1.47
c	0.40	0.50	0.65
D	15.10	15.60	16.10
D1	8.80	9.10	9.40
D2	5.50	-	-
E	9.70	10.00	10.30
E3	7.00	-	-
e	2.54 BSC		
e1	5.08 BSC		
H1	6.25	6.50	6.85
L	12.75	13.50	13.80
L1	-	3.10	3.40
ΦP	3.40	3.60	3.80
Q	2.60	2.80	3.00

Device Per Unit

Package Type	Unit	Quantity
TO-263-2L	Reel	50

Package Information

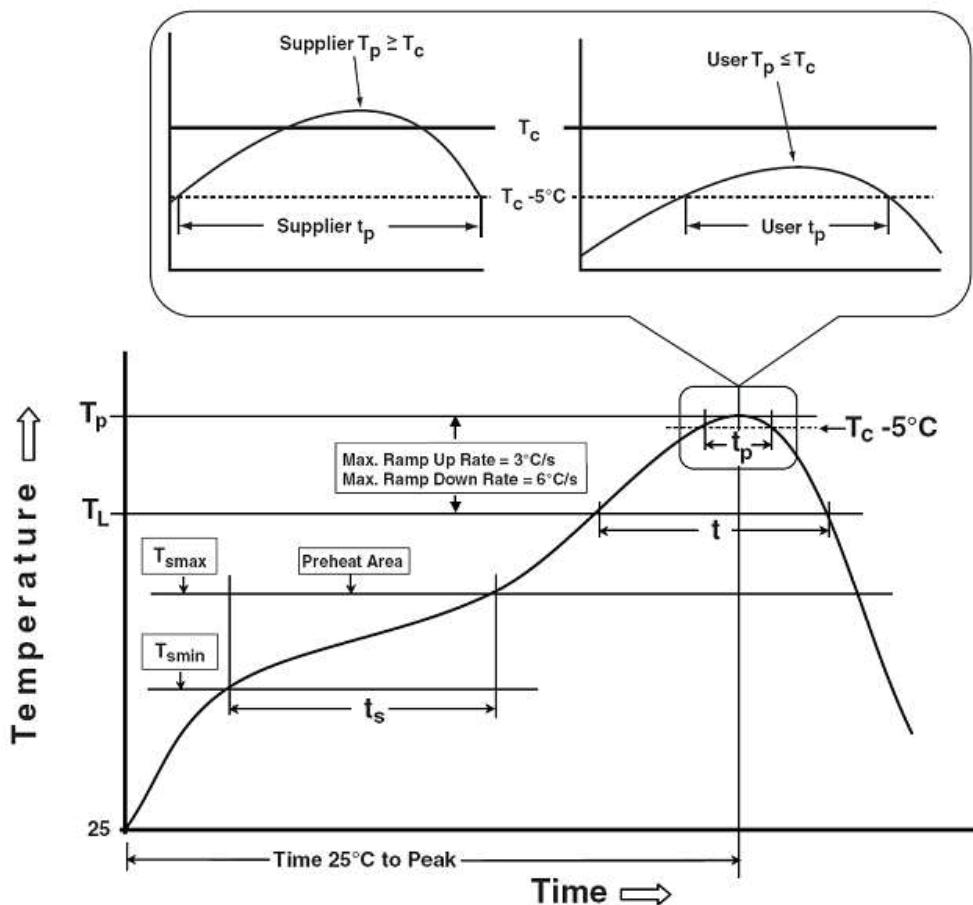
TO-263-2L



COMMON DIMENSIONS

SYMBOL	mm		
	MIN	NOM	MAX
A	4.37	4.57	4.77
A1	1.22	1.27	1.42
A2	2.49	2.69	2.89
A3	0	0.13	0.25
b	0.7	0.81	0.96
b1	1.17	1.27	1.47
c	0.3	0.38	0.53
D1	8.5	8.7	8.9
D4	6.6	-	-
E	9.86	10.16	10.36
E5	7.06	-	-
e	2.54 BSC		
H	14.7	15.1	15.5
H2	1.07	1.27	1.47
L	2	2.3	2.6
L1	1.4	1.55	1.7
L4	0.25 BSC		
θ	0°	5°	9°

Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak		
Temperature min (T_{smin})	100 °C	150 °C
Temperature max (T_{smax})	150 °C	200 °C
Time (T_{smin} to T_{smax}) (t_s)	60-120 seconds	60-120 seconds
Average ramp-up rate (T_{smax} to T_p)	3 °C/second max.	3 °C/second max.
Liquidous temperature (T_L)	183 °C	217 °C
Time at liquidous (t_L)	60-150 seconds	60-150 seconds
Peak package body Temperature (T_p)*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t_p)** within 5°C of the specified classification temperature (T_c)	20** seconds	30** seconds
Average ramp-down rate (T_p to T_{smax})	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.

*Tolerance for peak profile Temperature (T_p) is defined as a supplier minimum and a user maximum.

** Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.

Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ ≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	168 Hrs/500 Hrs/1000 Hrs, Bias @ 125°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -55°C~150°C